

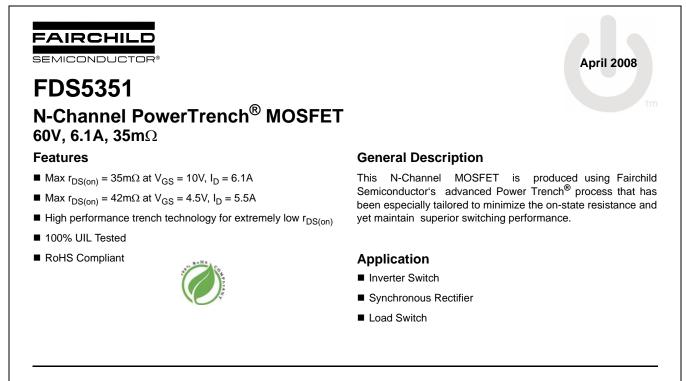
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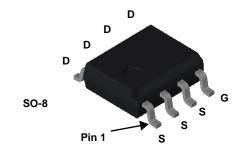


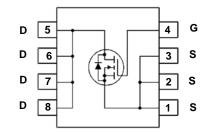
# **ON Semiconductor**®

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# **MOSFET Maximum Ratings** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units			
V <sub>DS</sub>	Drain to Source Voltage		60	V		
V <sub>GS</sub>	Gate to Source Voltage		±20	V		
	Drain Current -Continuous		6.1	•		
D	-Pulsed		30	A		
E <sub>AS</sub>	Single Pulse Avalanche Energy	(Note 3)	73	mJ		
D	Power Dissipation $T_A = 25^{\circ}C$	(Note 1a)	5	w		
PD	Power Dissipation $T_A = 25^{\circ}C$	(Note 1b)	2.5	vv		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C		

## **Thermal Characteristics**

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	25	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/vv

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS5351	FDS5351	SO-8	13"	12mm	2500units

FDS5351 N-Channel PowerTrench<sup>®</sup> MOSFET

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics				1	
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	60			V
$\Delta BV_{DSS}$	Breakdown Voltage Temperature	$I_D = 250 \mu A$ , referenced to 25°C		55		mV/°C
ΔT <sub>J</sub>	Coefficient Zero Gate Voltage Drain Current	$V_{DS} = 48V, V_{GS} = 0V$			1	μA
I <sub>DSS</sub>	Gate to Source Leakage Current	$V_{DS} = \pm 20V, V_{DS} = 0V$			±100	nA
I <sub>GSS</sub>		VGS - 1200, VDS - 00			100	10.4
On Chara	acteristics					1
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \mu A$	1.0	2.0	3.0	V
$\Delta V_{GS(th)}$ $\Delta T_J$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu A$ , referenced to $25^{\circ}C$		-6.2		mV/°C
		$V_{GS} = 10V, I_D = 6.1A$		26.5	35.0	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 4.5 V, I_D = 5.5 A$		32.4	42.0	mΩ
		$V_{GS} = 10V, I_D = 6.1A, T_J = 125^{\circ}C$		44.5	58.8	
9 <sub>FS</sub>	Forward Transconductance	$V_{DD} = 5V, I_D = 6.1A$		24		S
Dvnamic	Characteristics					
C <sub>iss</sub>	Input Capacitance			985	1310	pF
C <sub>oss</sub>	Output Capacitance	$-V_{DS} = 30V, V_{GS} = 0V,$		90	120	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1MHz		50	75	pF
R <sub>g</sub>	Gate Resistance	f = 1MHz		1.7	10	Ω
*						
	g Characteristics			8	16	20
t <sub>d(on)</sub>	Turn-On Delay Time Rise Time	V <sub>DD</sub> = 30V, I <sub>D</sub> = 6.1A,		3	10	ns ns
t <sub>r</sub>	Turn-Off Delay Time	$-V_{GS} = 10V, R_{GEN} = 6\Omega$		21	34	ns
t <sub>d(off)</sub>	Fall Time	-		2	10	ns
t <sub>f</sub>	Total Gate Charge	V <sub>GS</sub> = 0V to 10V		19	27	nC
Q <sub>g</sub>	Total Gate Charge	$V_{GS} = 0V \text{ to } 10V$ $V_{DD} = 30V,$		9	13	nC
Q <sub>g</sub>	Gate to Source Charge	$V_{\text{GS}} = 0V \text{ to } 4.5V$ $V_{\text{DD}} = 30V,$ $I_{\text{D}} = 6.1A$		3	15	nC
Q <sub>gs</sub>	Gate to Drain "Miller" Charge	-		3.5		nC
Q <sub>gd</sub>				5.5		no
Drain-So	urce Diode Characteristics					
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 6.1A$ (Note 2) $V_{GS} = 0V, I_S = 2.1A$ (Note 2)		0.82	1.3 1.2	V
	Reverse Recovery Time			0.76 24	38	ns
ter		— I <sub>F</sub> = 6.1A, di/dt = 100A/μs		15	27	nC
t <sub>rr</sub> Q <sub>rr</sub>	Reverse Recovery Charge					

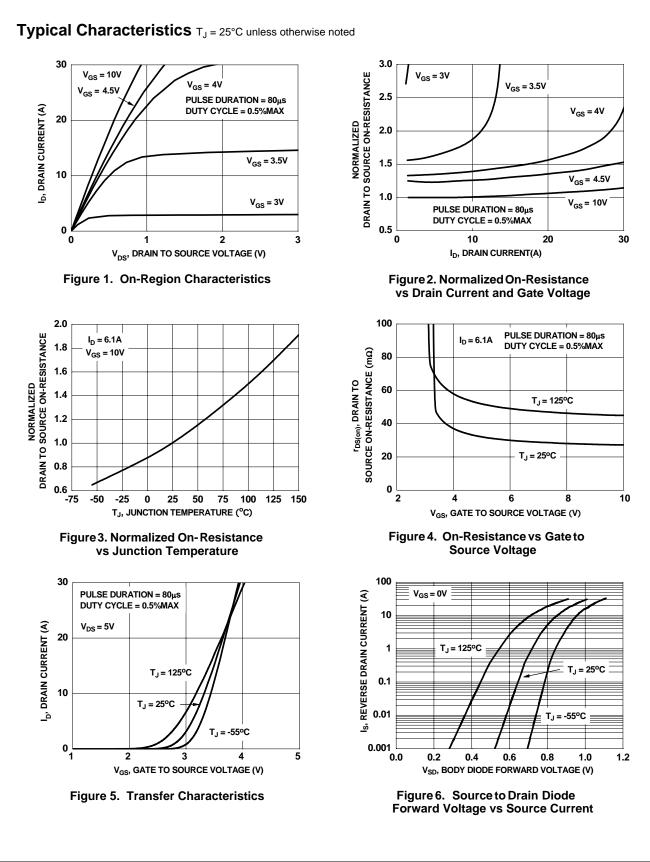
2. Pulse Test: Pulse Width < 300 $\mu s,$  Duty cycle < 2.0%.

3. UIL condition: Starting  $T_J$  = 25°C, L = 3mH,  $I_{AS}$  = 7A,  $V_{DD}$  = 60V,  $V_{GS}$  = 10V.

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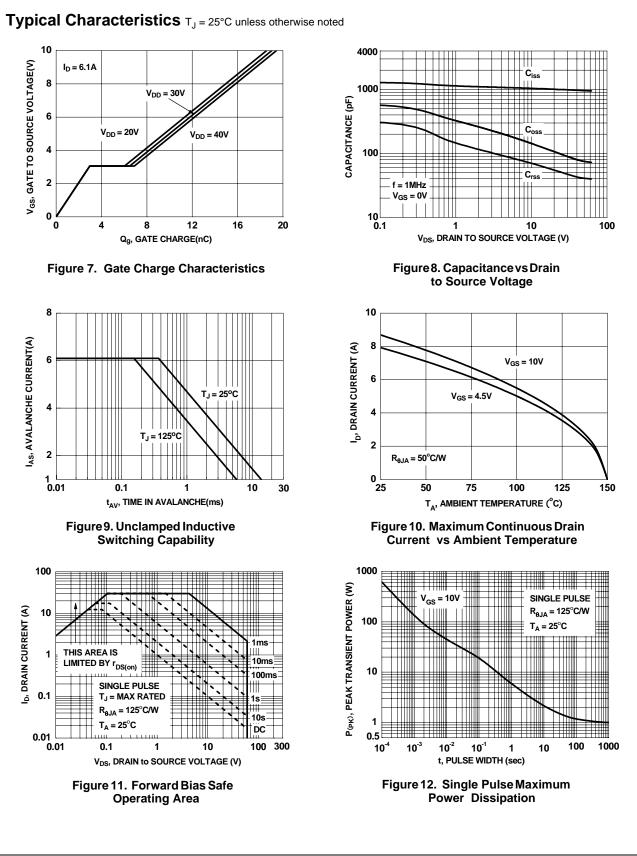
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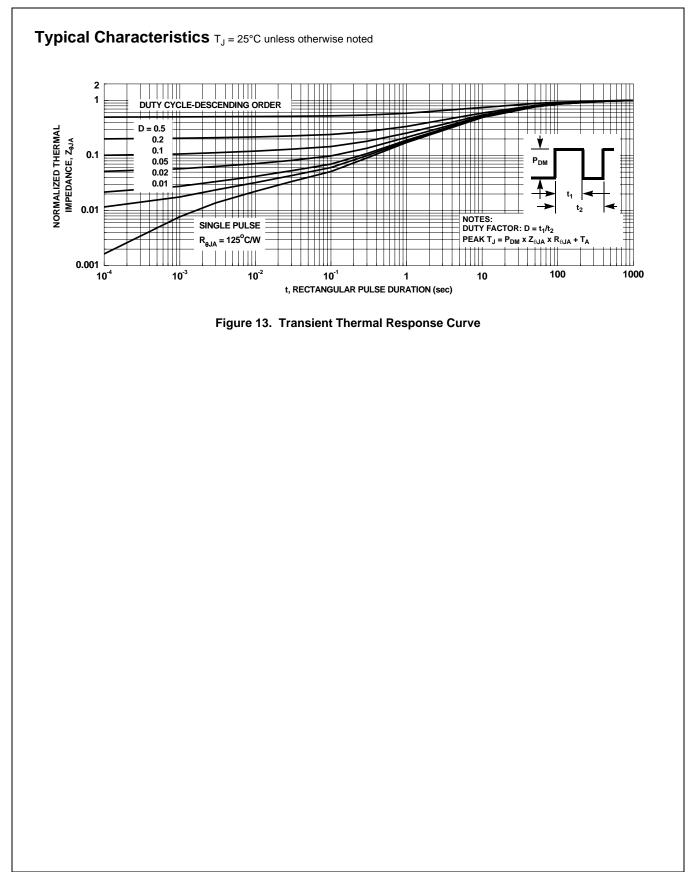


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